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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Hiroyuki HARA

Group Art Unit: 2858

Application No.: 10/808,523

Examiner: M. KRAMSKAYA

Filed: March 25, 2004

Docket No.: 119243

For: CAPACITANCE DETECTION DEVICE AND DRIVE METHOD THEREOF,
FINGERPRINT SENSOR, AND BIOMETRICS AUTHENTICATION DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection, Notice of Allowance or other action that closes prosecution (e.g., Quayle Action).
- ☒ a. I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement. 37 CFR §1.97(e)(1).
- ☒ 2. The references were cited in two counterpart foreign applications. An English language version of one foreign search report is attached for the Examiner's information.
- ☒ 3. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 4. English language Abstracts of the non-English language references are attached hereto.

- ☒ 5. A computer-generated English language translation of the following Japanese Patent Publication has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 6-8.

Respectfully submitted,



James A. Oliff
Registration No. 27,075

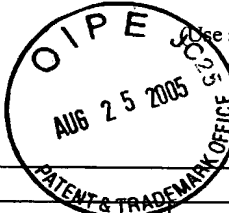
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JAO:GXL/sqb

Date: August 25, 2005

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Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 119243		APPLICATION NO. 10/808,523	
INFORMATION DISCLOSURE STATEMENT				APPLICANT Hiroyuki HARA			
(See several sheets if necessary)							
				FILING DATE March 25, 2004		GROUP 2858	
				U.S. PATENT DOCUMENTS			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
	1	4,429,413	01/31/1984	David G. EDWARDS			
	2	6,049,620	04/11/2000	Alexander G. DICKINSON			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
	3	EP 1 041 356 A1	10/04/2000	Europe			
	4	EP 0 969 477 A1	01/05/2000	Europe			
	5	JP A 58-27277 (w/Partial Eng. Trans. & Corresponding to U.S. 4,429,413)	02/17/1983	Japan			
	6	JP A 2000-028311 (w/Eng. Abstract and Translation)	01/28/2000	Japan			
	7	JP A 2002-340517 (w/Eng. Abstract and Translation)	11/27/2002	Japan			
	8	JP A 2003-090703 (w/Eng. Abstract and Translation)	03/28/2003	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	9	Hiroyuki HARA et al., "Low Temperature Polycrystalline Silicon TFT Fingerprint Sensor with Integrated Comparator Circuit", IEEE, September 21-23, 2004, pages 403-406.					
	10	Ryuichi HASHIDO et al., "A Capacitive Fingerprint Sensor Chip Using Low-Temperature Poly-Si TFTs on a Glass Substrate and a Novel and Unique Sensing Method", IEEE JOURNAL OF SOLID-STATE CIRCUITS, February 2003,					
		vol. 38, no. 2, pages 274-280.					
EXAMINER				DATE CONSIDERED			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: August 25, 2005